

CDMA 1X Test Position 6 Middle

Electronics: DAE3 Sn536

Communication System: CDMA 1X-new Frequency: 836.52 MHz Duty Cycle: 1:1

Probe: ET3DV6 - SN1736 ConvF(6.45, 6.45, 6.45)

Test Position 6 Middle/Area Scan (61x131x1): Measurement grid: dx=10mm, dy=10mm

Maximum value of SAR (interpolated) = 0.312 mW/g

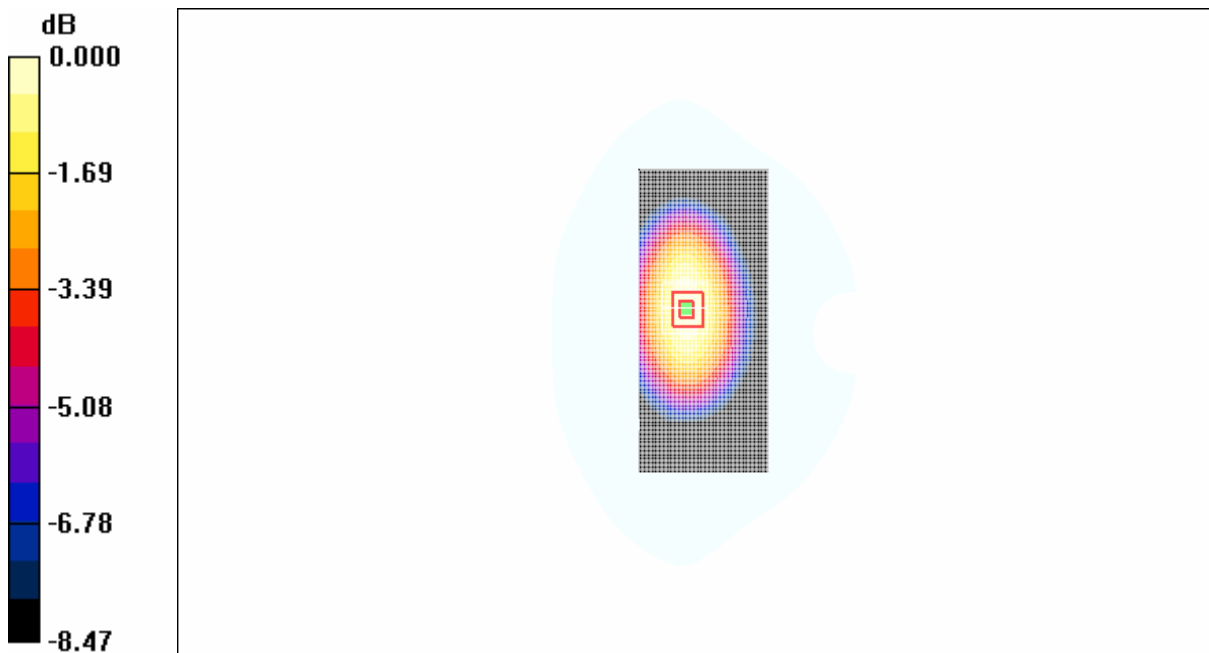
Test Position 6 Middle/Zoom Scan (7x7x7)/Cube 0: Measurement grid: dx=5mm, dy=5mm, dz=5mm

Reference Value = 17.3 V/m; Power Drift = -0.114 dB

Peak SAR (extrapolated) = 0.371 W/kg

SAR(1 g) = 0.293 mW/g; SAR(10 g) = 0.214 mW/g

Maximum value of SAR (measured) = 0.311 mW/g



0 dB = 0.311mW/g

Fig. 11 Test Position 6 CDMA 835MHz CH384

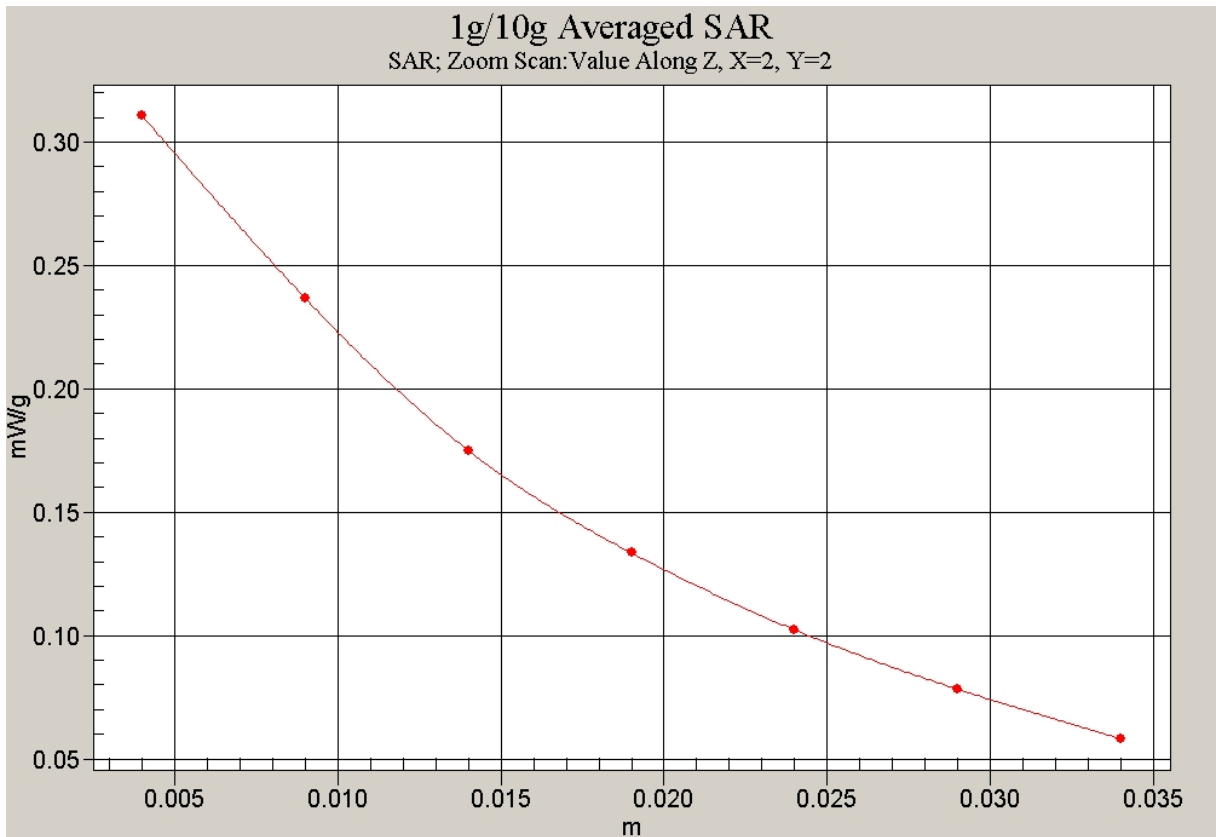


Fig. 12 Z-Scan at power reference point (CDMA 835MHz CH384)

CDMA 1X Test Position 7 Middle

Electronics: DAE3 Sn536

Communication System: CDMA 1X-new Frequency: 836.52 MHz Duty Cycle: 1:1

Probe: ET3DV6 - SN1736 ConvF(6.45, 6.45, 6.45)

Test Position 7 Middle/Area Scan (61x131x1): Measurement grid: dx=10mm, dy=10mm

Maximum value of SAR (interpolated) = 0.367 mW/g

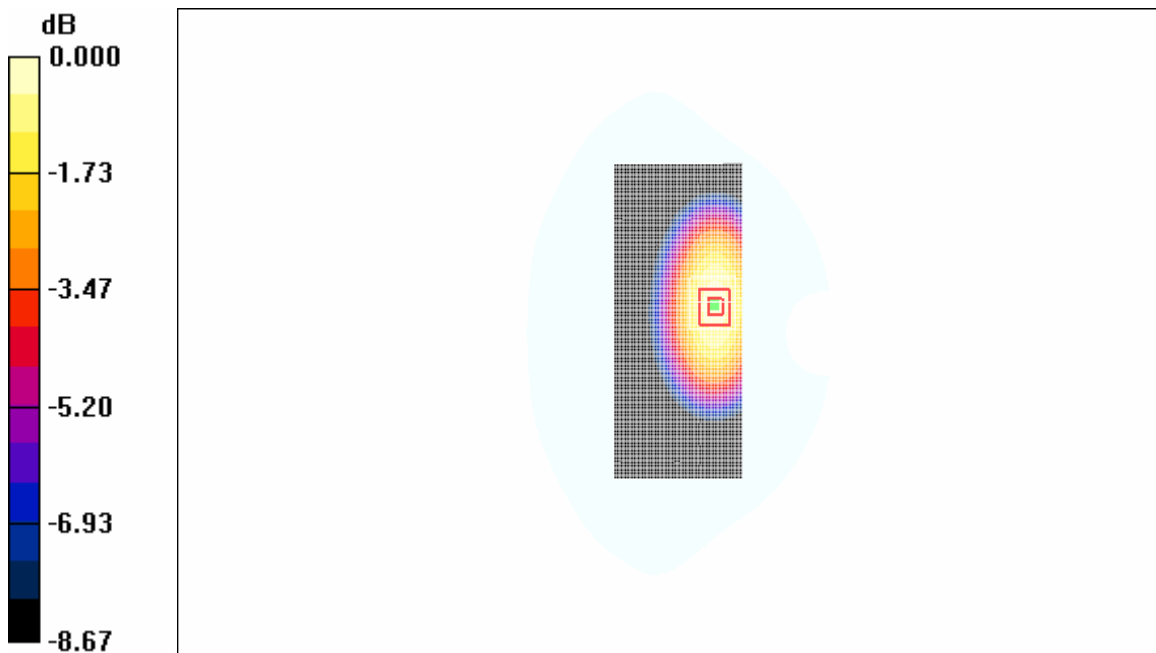
Test Position 7 Middle/Zoom Scan (7x7x7)/Cube 0: Measurement grid: dx=5mm, dy=5mm, dz=5mm

Reference Value = 14.3 V/m; Power Drift = 0.200 dB

Peak SAR (extrapolated) = 0.473 W/kg

SAR(1 g) = 0.367 mW/g; SAR(10 g) = 0.267 mW/g

Maximum value of SAR (measured) = 0.388 mW/g



0 dB = 0.388mW/g

Fig. 13 Test Position 7 CDMA 835MHz CH384

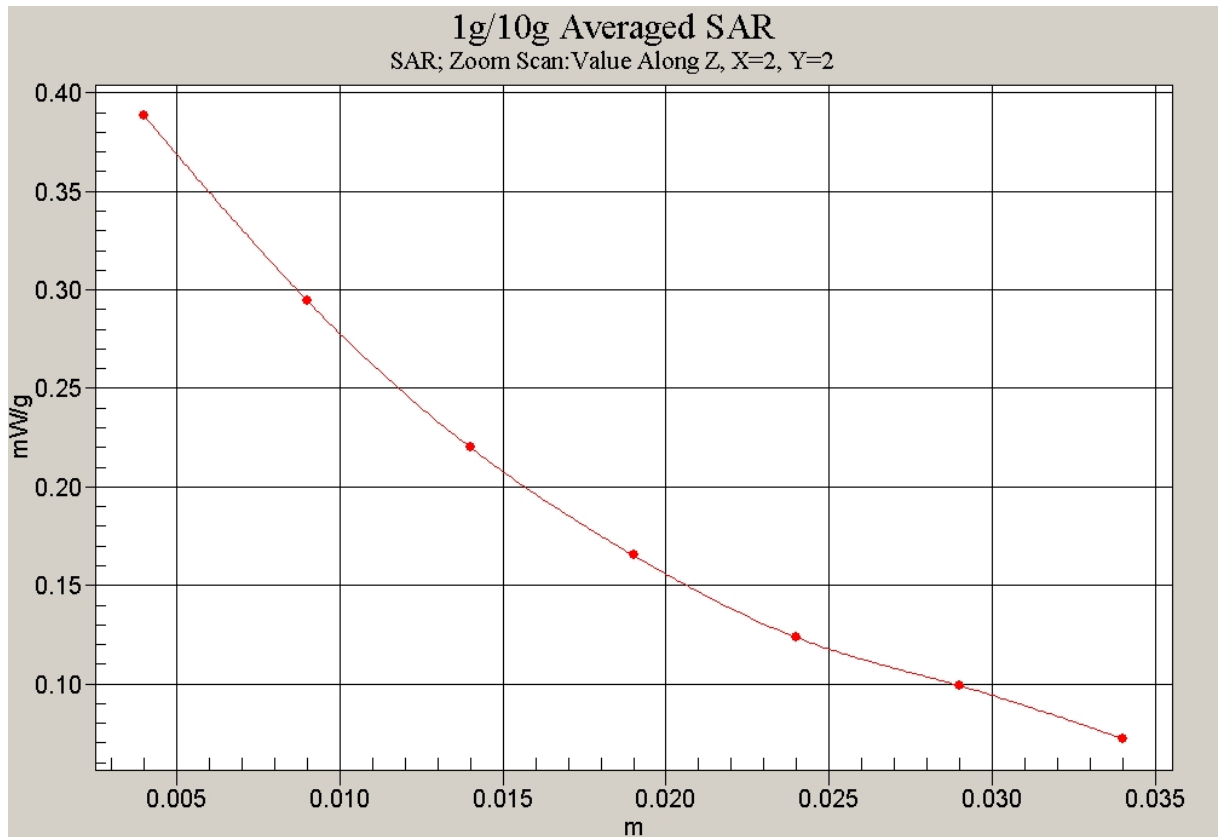


Fig. 14 Z-Scan at power reference point (CDMA 835MHz CH384)

CDMA 1X Test Position 8 Middle

Electronics: DAE3 Sn536

Communication System: CDMA 1X-new Frequency: 836.52 MHz Duty Cycle: 1:1

Probe: ET3DV6 - SN1736 ConvF(6.45, 6.45, 6.45)

Test Position 8 Middle/Area Scan (71x131x1): Measurement grid: dx=10mm, dy=10mm

Maximum value of SAR (interpolated) = 0.046 mW/g

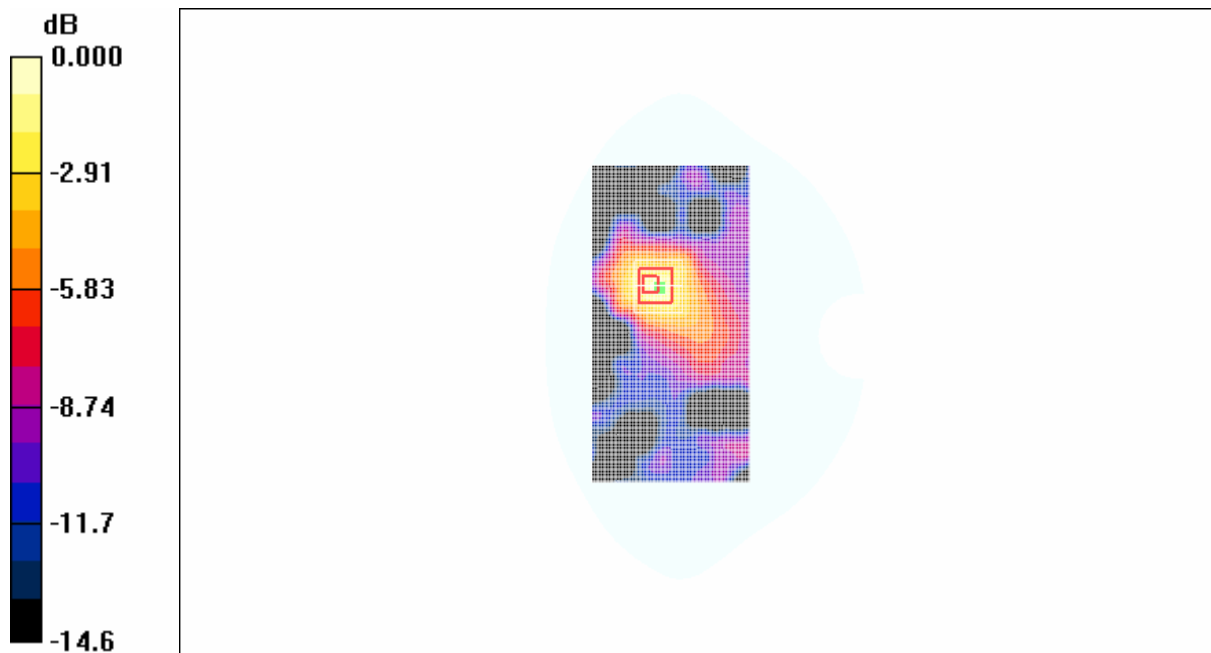
Test Position 8 Middle/Zoom Scan (7x7x7)/Cube 0: Measurement grid: dx=5mm, dy=5mm, dz=5mm

Reference Value = 4.12 V/m; Power Drift = -0.092 dB

Peak SAR (extrapolated) = 0.086 W/kg

SAR(1 g) = 0.043 mW/g; SAR(10 g) = 0.024 mW/g

Maximum value of SAR (measured) = 0.051 mW/g



0 dB = 0.051mW/g

Fig.15 Test Position 8 CDMA 835MHz CH384

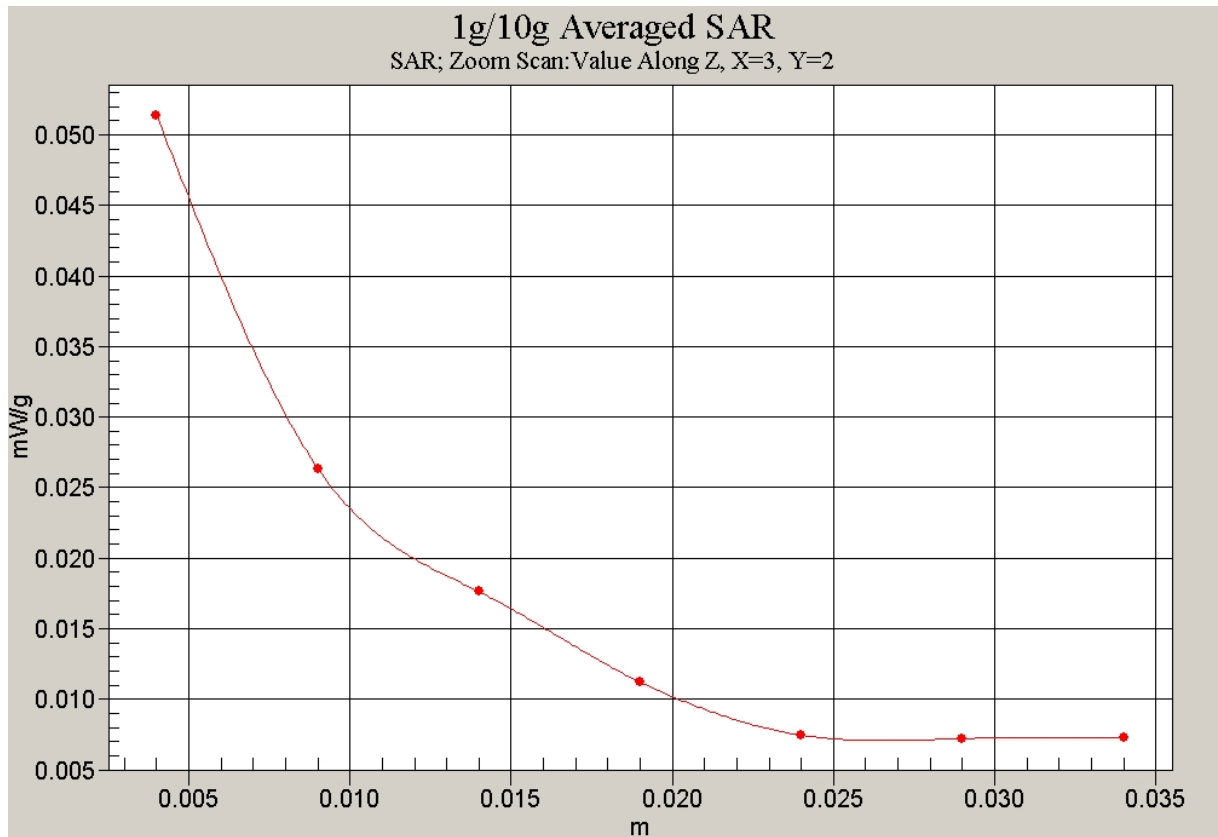


Fig. 16 Z-Scan at power reference point (CDMA 835MHz CH384)

CDMA 1X Test Position 9 Middle

Electronics: DAE3 Sn536

Communication System: CDMA 1X-new Frequency: 836.52 MHz Duty Cycle: 1:1

Probe: ET3DV6 - SN1736 ConvF(6.45, 6.45, 6.45)

Test Position 9 Middle/Area Scan (61x131x1): Measurement grid: dx=10mm, dy=10mm

Maximum value of SAR (interpolated) = 0.386 mW/g

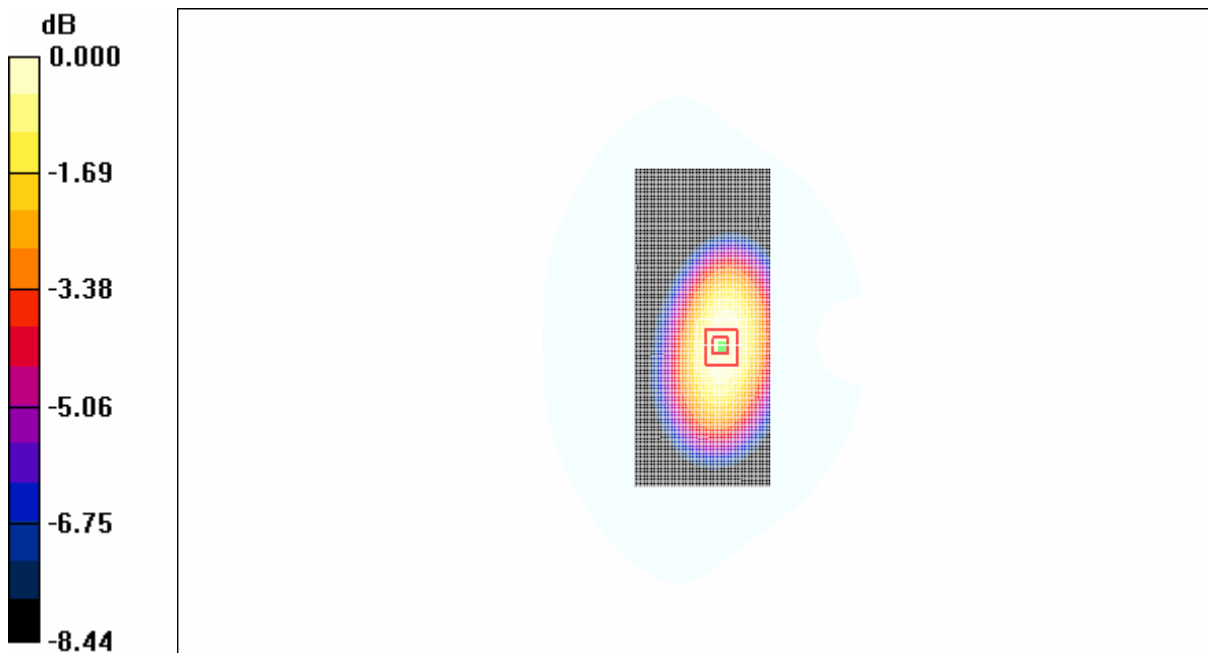
Test Position 9 Middle/Zoom Scan (7x7x7)/Cube 0: Measurement grid: dx=5mm, dy=5mm, dz=5mm

Reference Value = 19.3 V/m; Power Drift = -0.181 dB

Peak SAR (extrapolated) = 0.450 W/kg

SAR(1 g) = 0.355 mW/g; SAR(10 g) = 0.259 mW/g

Maximum value of SAR (measured) = 0.375 mW/g



0 dB = 0.375mW/g

Fig. 17 Test Position 9 CDMA 835MHz CH384

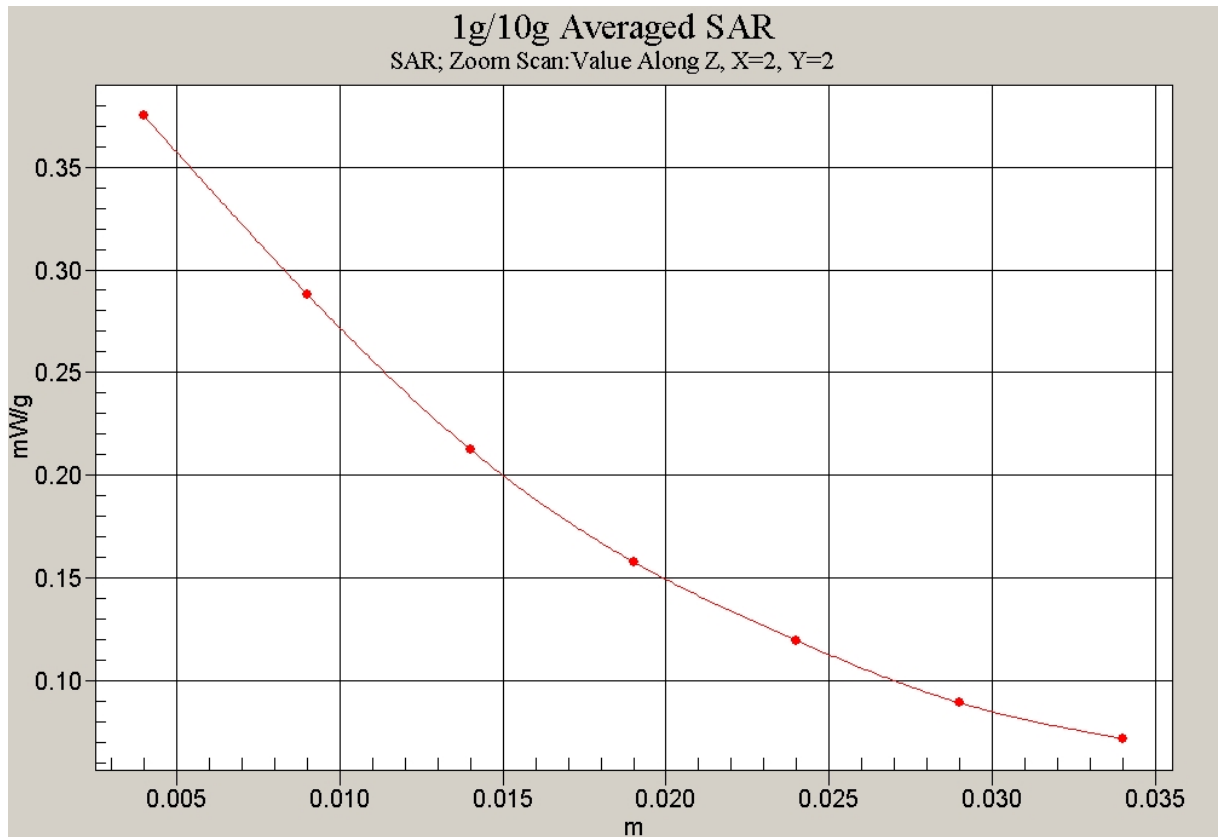


Fig. 18 Z-Scan at power reference point (CDMA 835MHz CH384)

CDMA 1X Test Position 10 Middle

Electronics: DAE3 Sn536

Communication System: CDMA 1X-new Frequency: 836.52 MHz Duty Cycle: 1:1

Probe: ET3DV6 - SN1736 ConvF(6.45, 6.45, 6.45)

Test Position 10 Middle/Area Scan (61x131x1): Measurement grid: dx=10mm, dy=10mm

Maximum value of SAR (interpolated) = 0.736 mW/g

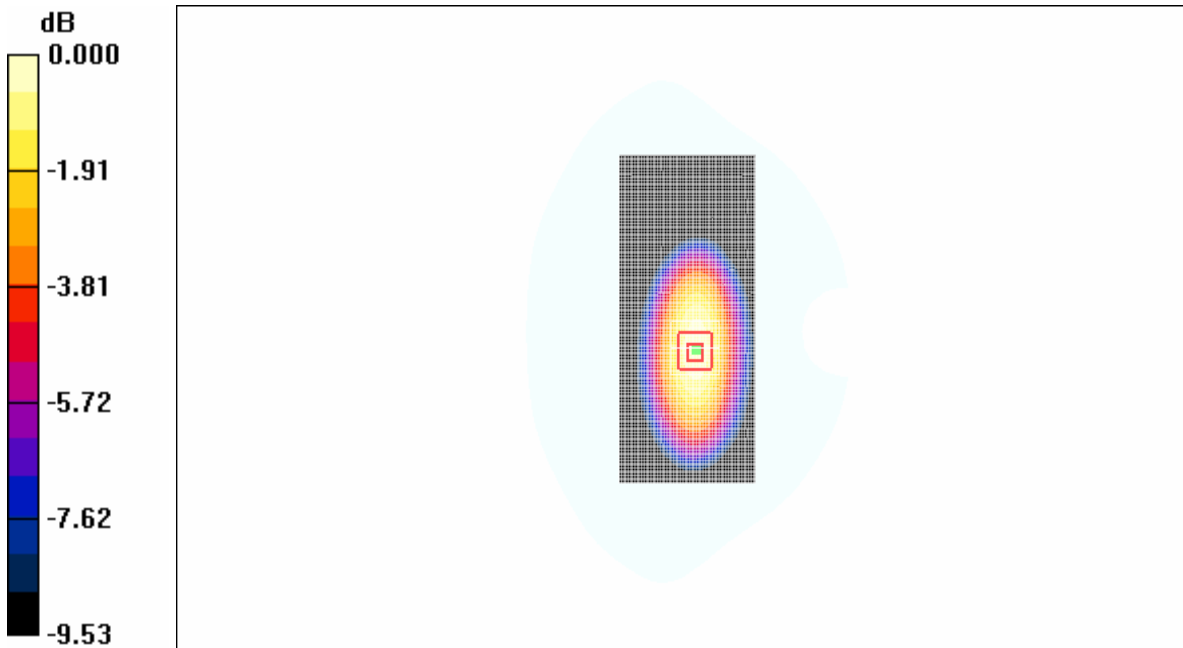
Test Position 10 Middle/Zoom Scan (7x7x7)/Cube 0: Measurement grid: dx=5mm, dy=5mm, dz=5mm

Reference Value = 27.7 V/m; Power Drift = 0.011 dB

Peak SAR (extrapolated) = 0.958 W/kg

SAR(1 g) = 0.703 mW/g; SAR(10 g) = 0.484 mW/g

Maximum value of SAR (measured) = 0.753 mW/g



0 dB = 0.753mW/g

Fig. 19 Test Position 10 CDMA 835MHz CH384

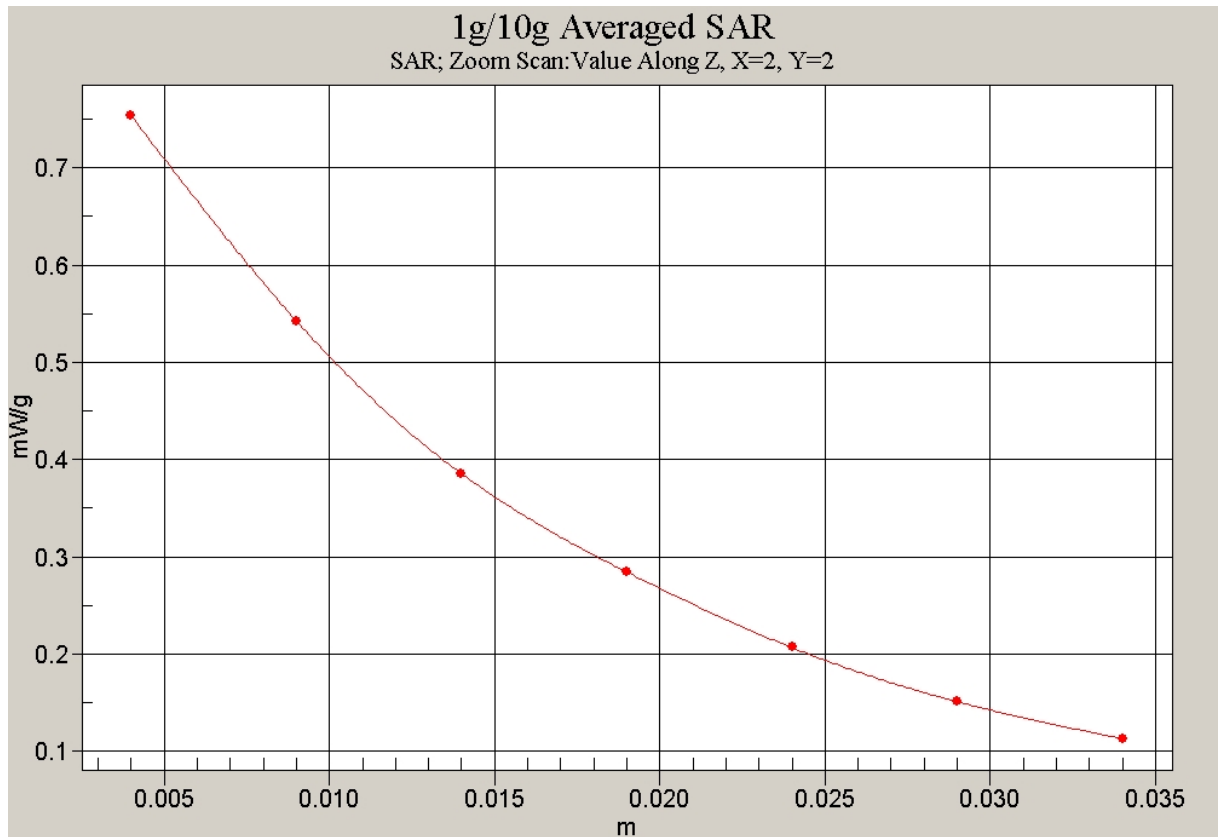


Fig. 20 Z-Scan at power reference point (CDMA 835MHz CH384)

CDMA 1X Test Position 11 Middle

Electronics: DAE3 Sn536

Communication System: CDMA 1X-new Frequency: 836.52 MHz Duty Cycle: 1:1

Probe: ET3DV6 - SN1736 ConvF(6.45, 6.45, 6.45)

Test Position 11 Middle/Area Scan (61x131x1): Measurement grid: dx=10mm, dy=10mm

Maximum value of SAR (interpolated) = 0.735 mW/g

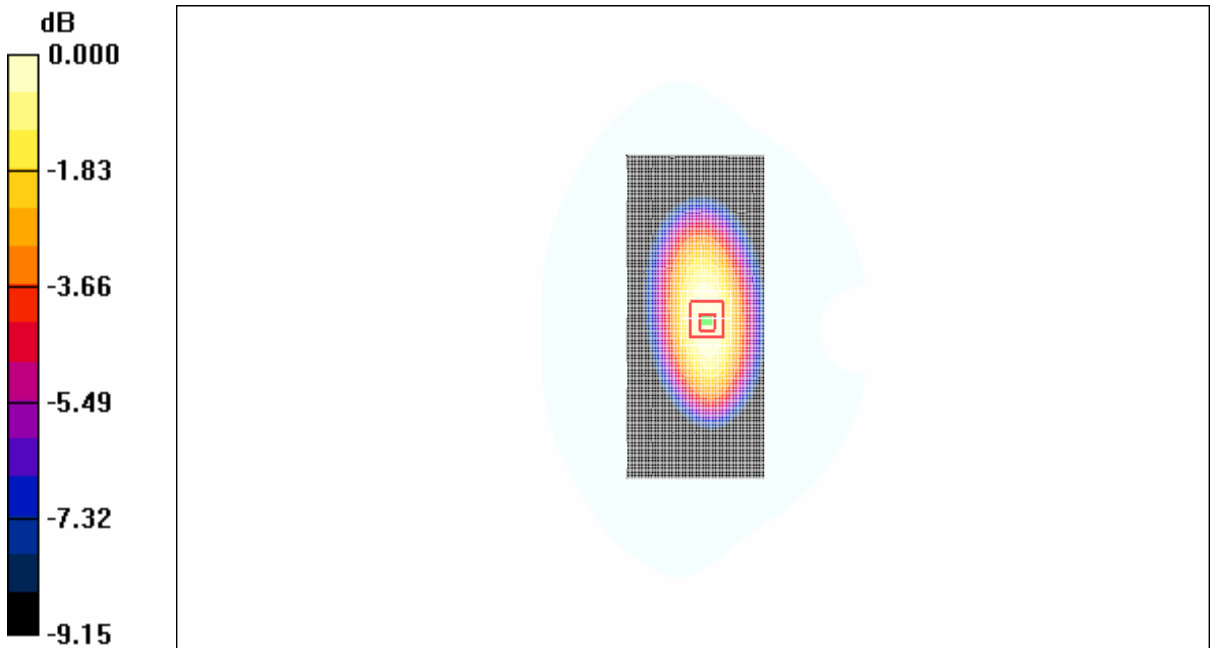
Test Position 11 Middle/Zoom Scan (7x7x7)/Cube 0: Measurement grid: dx=5mm, dy=5mm, dz=5mm

Reference Value = 29.0 V/m; Power Drift = -0.094 dB

Peak SAR (extrapolated) = 0.880 W/kg

SAR(1 g) = 0.666 mW/g; SAR(10 g) = 0.468 mW/g

Maximum value of SAR (measured) = 0.707 mW/g



0 dB = 0.707mW/g

Fig. 21 Test Position 11 CDMA 835MHz CH384

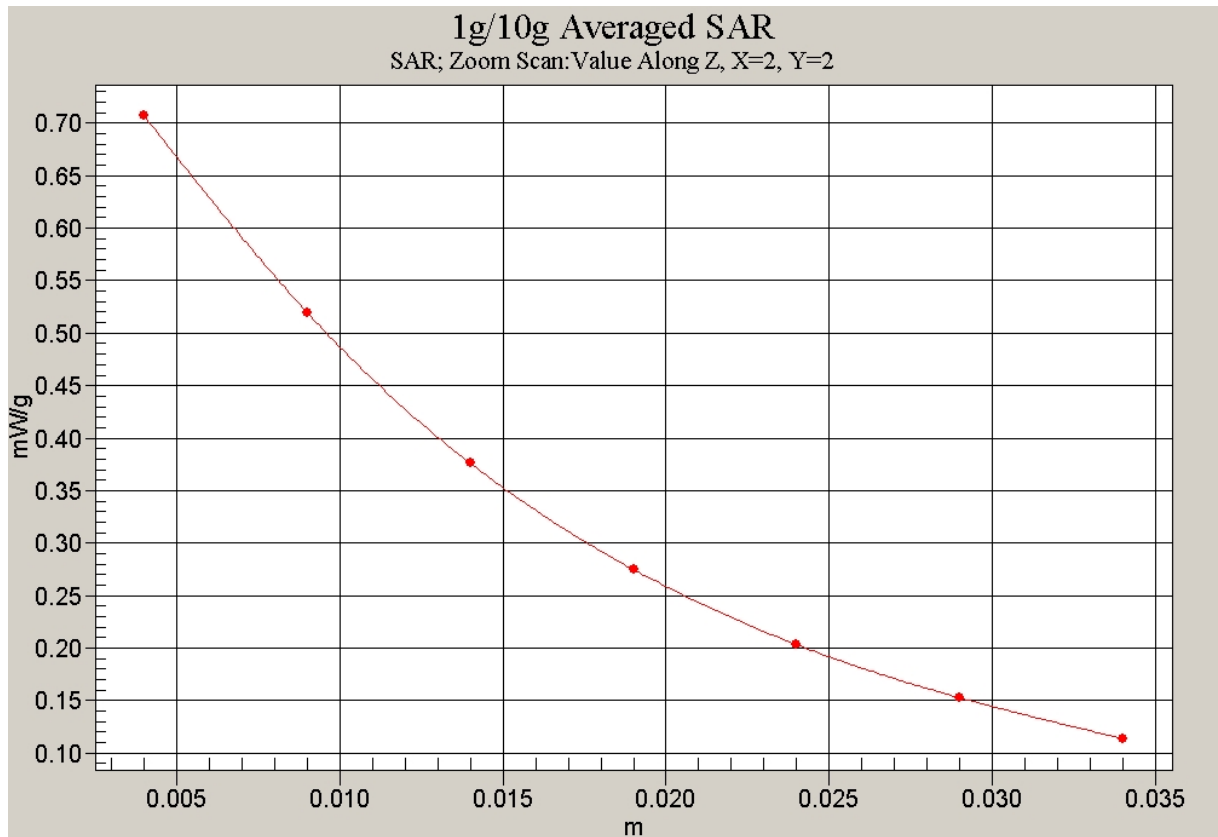


Fig. 22 Z-Scan at power reference point (CDMA 835MHz CH384)

CDMA 1X Test Position 12 Middle

Electronics: DAE3 Sn536

Communication System: CDMA 1X-new Frequency: 836.52 MHz Duty Cycle: 1:1

Probe: ET3DV6 - SN1736 ConvF(6.45, 6.45, 6.45)

Test Position 12 Middle/Area Scan (81x131x1): Measurement grid: dx=10mm, dy=10mm

Maximum value of SAR (interpolated) = 0.692 mW/g

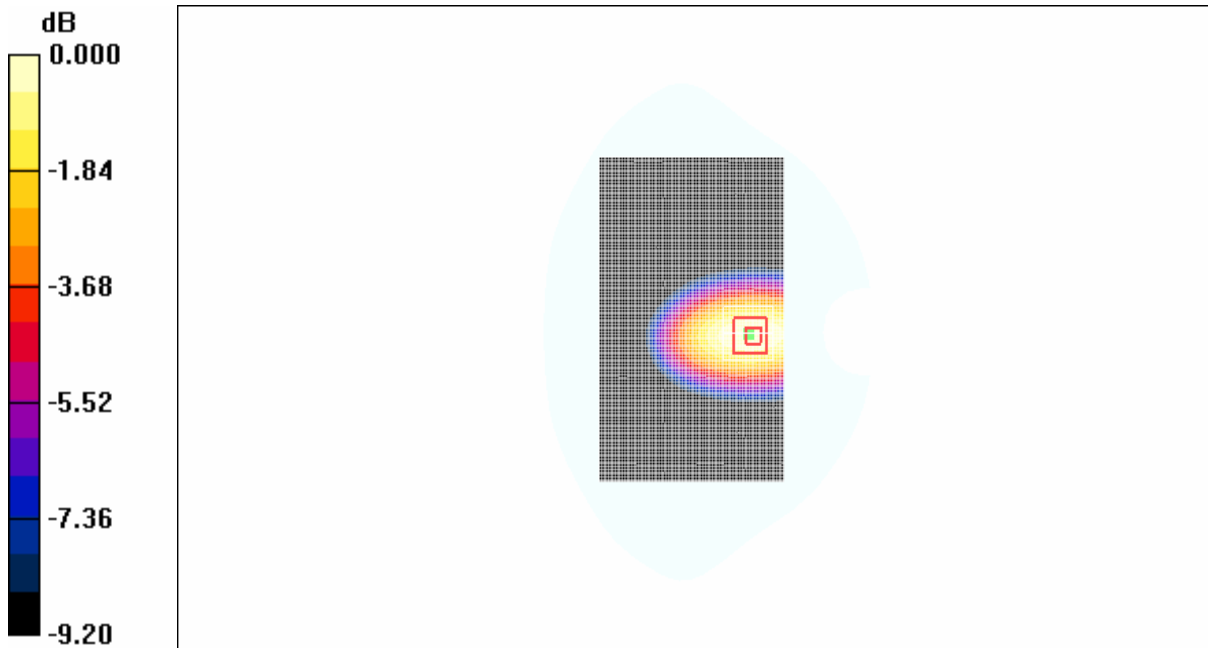
Test Position 12 Middle/Zoom Scan (7x7x7)/Cube 0: Measurement grid: dx=5mm, dy=5mm, dz=5mm

Reference Value = 24.4 V/m; Power Drift = -0.010 dB

Peak SAR (extrapolated) = 0.862 W/kg

SAR(1 g) = 0.641 mW/g; SAR(10 g) = 0.447 mW/g

Maximum value of SAR (measured) = 0.682 mW/g



0 dB = 0.682mW/g

Fig. 23 Test Position 12 CDMA 835MHz CH384

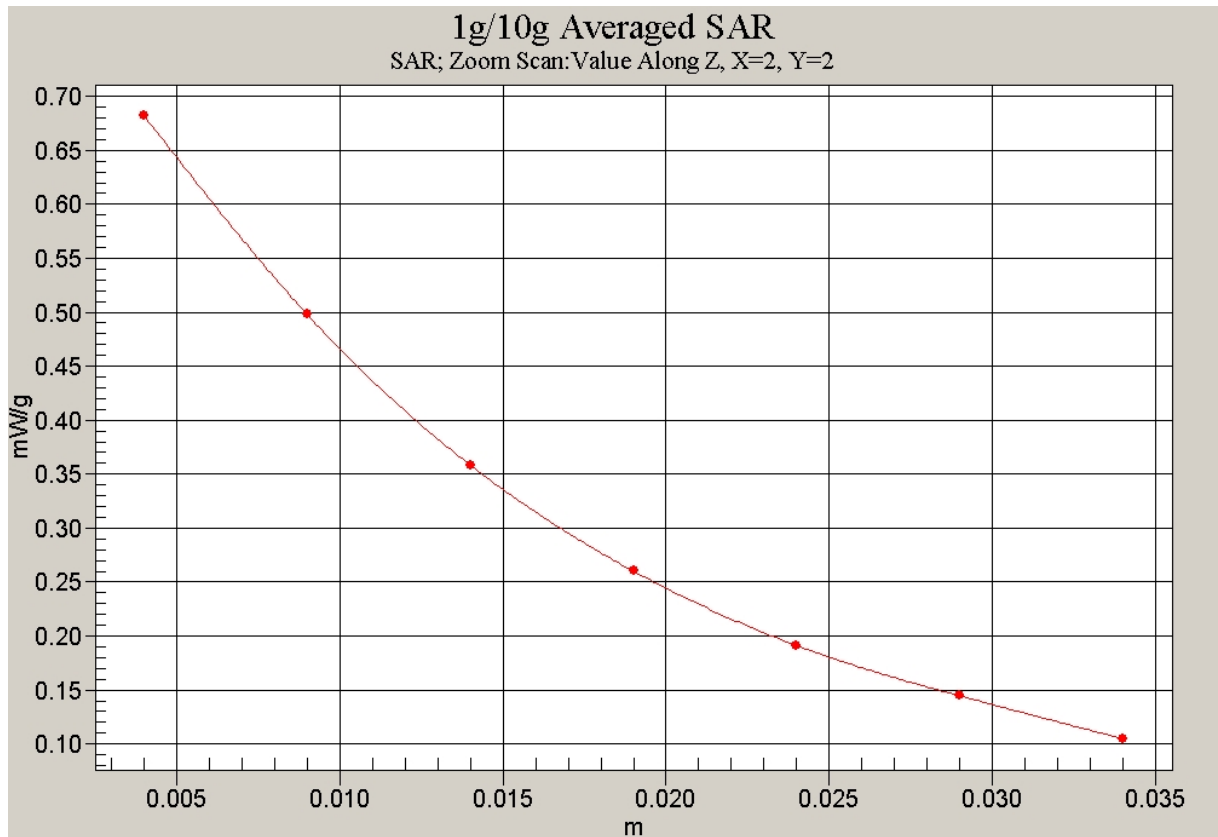


Fig. 24 Z-Scan at power reference point (CDMA 835MHz CH384)

CDMA 1X Test Position 13 High

Electronics: DAE3 Sn536

Communication System: CDMA 1X-new Frequency: 848.31 MHz Duty Cycle: 1:1

Probe: ET3DV6 - SN1736 ConvF(6.45, 6.45, 6.45)

Test Position 13 High/Area Scan (81x131x1): Measurement grid: dx=10mm, dy=10mm

Maximum value of SAR (interpolated) = 0.453 mW/g

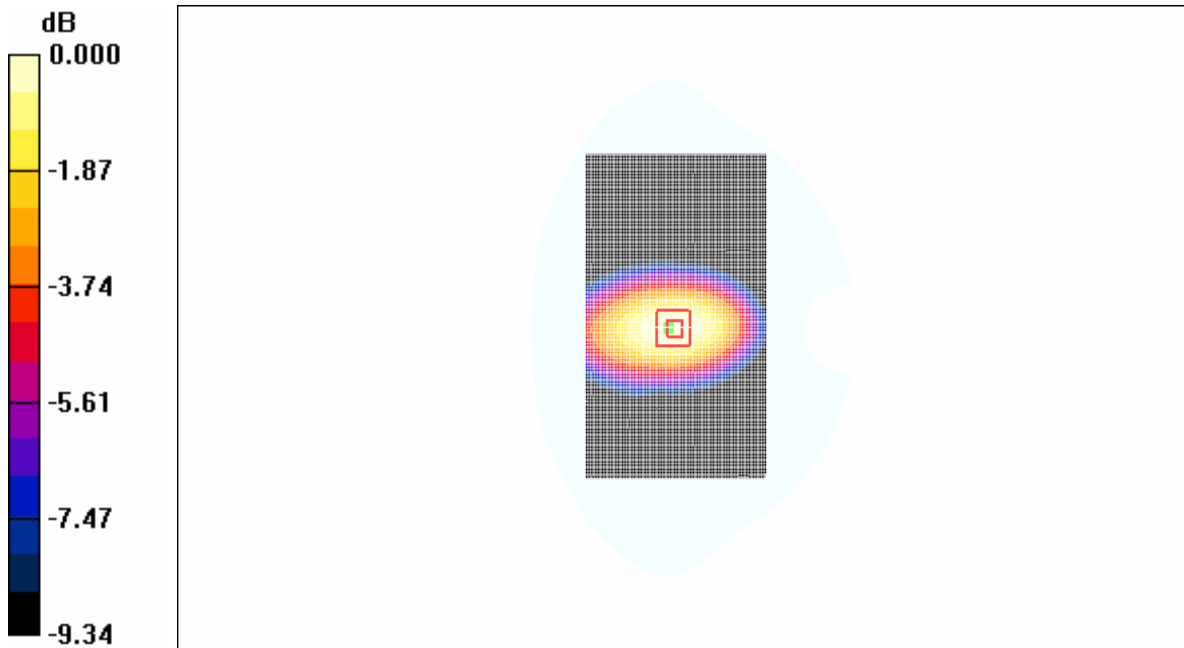
Test Position 13 High/Zoom Scan (7x7x7)/Cube 0: Measurement grid: dx=5mm, dy=5mm, dz=5mm

Reference Value = 22.6 V/m; Power Drift = -0.187 dB

Peak SAR (extrapolated) = 0.548 W/kg

SAR(1 g) = 0.415 mW/g; SAR(10 g) = 0.290 mW/g

Maximum value of SAR (measured) = 0.444 mW/g



0 dB = 0.444mW/g

Fig. 25 Test Position 13 CDMA 835MHz CH777

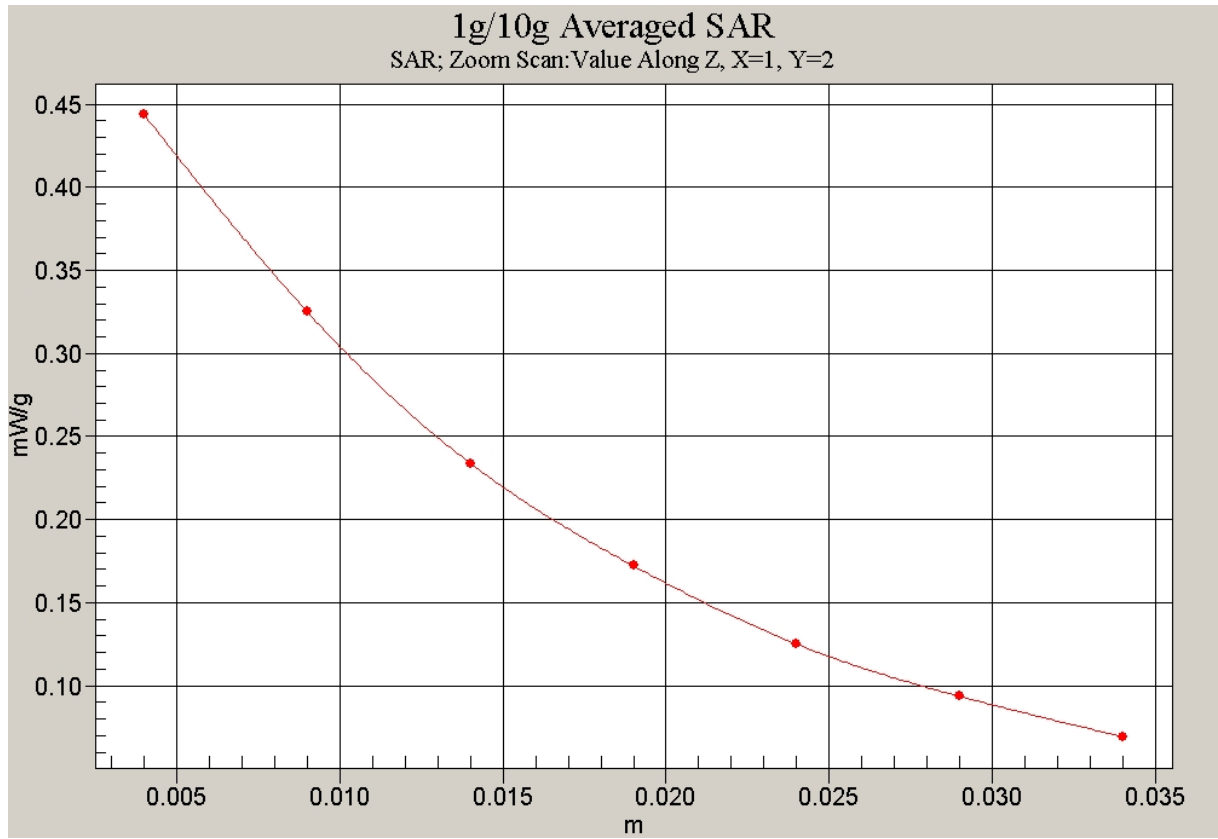


Fig. 26 Z-Scan at power reference point (CDMA 835MHz CH777)

CDMA 1X Test Position 13 Middle

Electronics: DAE3 Sn536

Communication System: CDMA 1X-new Frequency: 836.52 MHz Duty Cycle: 1:1

Probe: ET3DV6 - SN1736 ConvF(6.45, 6.45, 6.45)

Test Position 13 Middle/Area Scan (81x131x1): Measurement grid: dx=10mm, dy=10mm

Maximum value of SAR (interpolated) = 0.764 mW/g

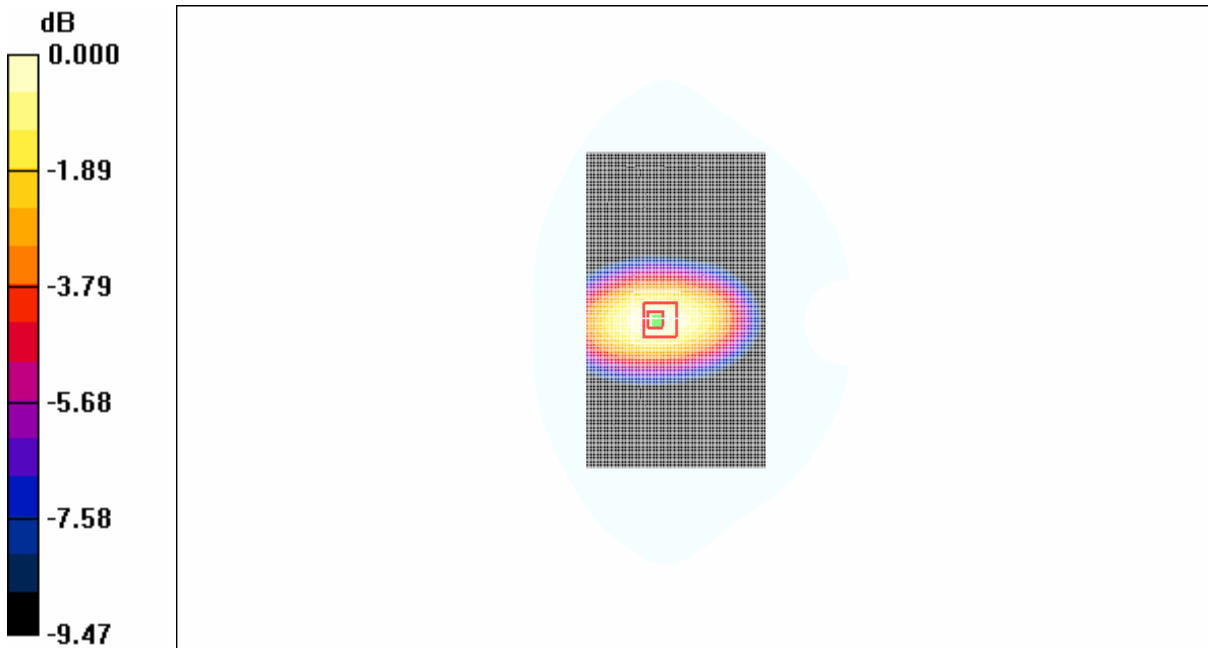
Test Position 13 Middle/Zoom Scan (7x7x7)/Cube 0: Measurement grid: dx=5mm, dy=5mm, dz=5mm

Reference Value = 28.0 V/m; Power Drift = -0.071 dB

Peak SAR (extrapolated) = 0.958 W/kg

SAR(1 g) = 0.708 mW/g; SAR(10 g) = 0.494 mW/g

Maximum value of SAR (measured) = 0.757 mW/g



0 dB = 0.757mW/g

Fig. 27 Test Position 13 CDMA 835MHz CH384

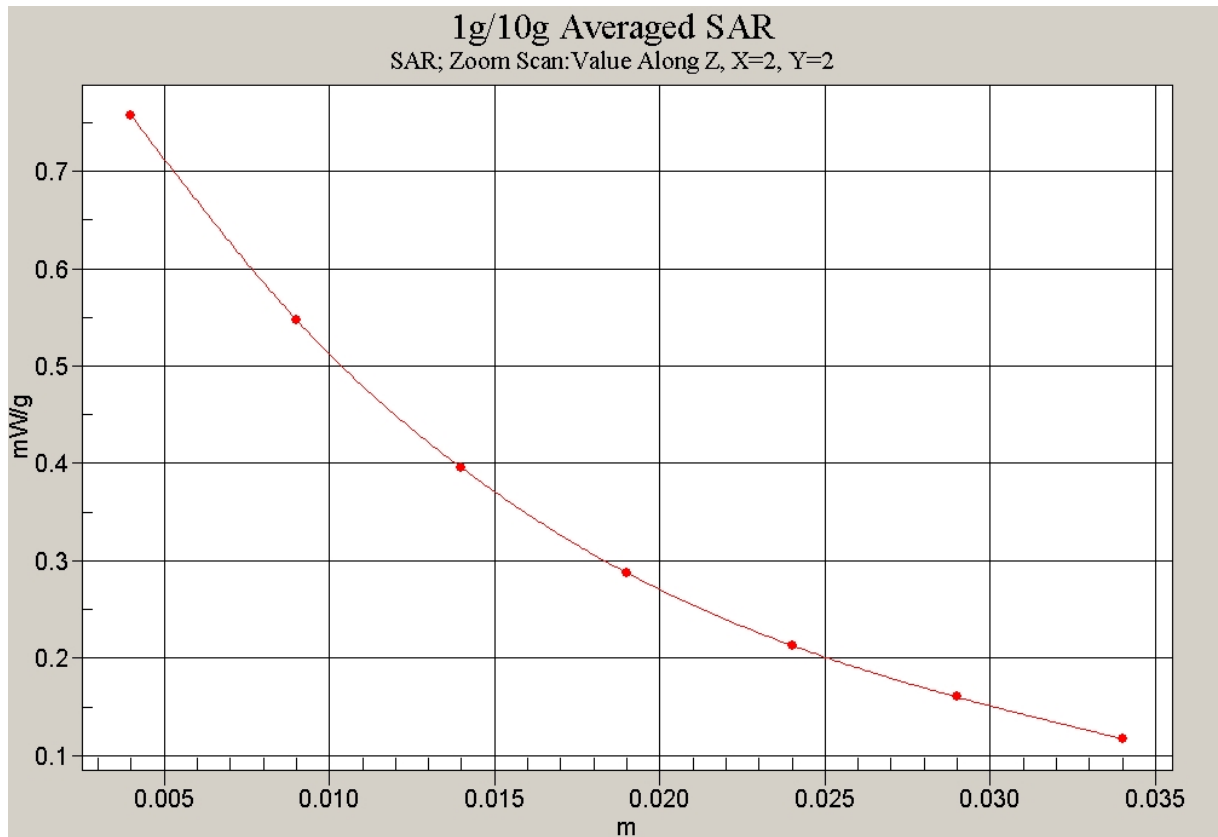


Fig. 28 Z-Scan at power reference point (CDMA 835MHz CH384)

CDMA 1X Test Position 13 Low

Electronics: DAE3 Sn536

Communication System: CDMA 1X-new Frequency: 824.7 MHz Duty Cycle: 1:1

Probe: ET3DV6 - SN1736 ConvF(6.45, 6.45, 6.45)

Test Position 13 Low/Area Scan (81x131x1): Measurement grid: dx=10mm, dy=10mm

Maximum value of SAR (interpolated) = 1.06 mW/g

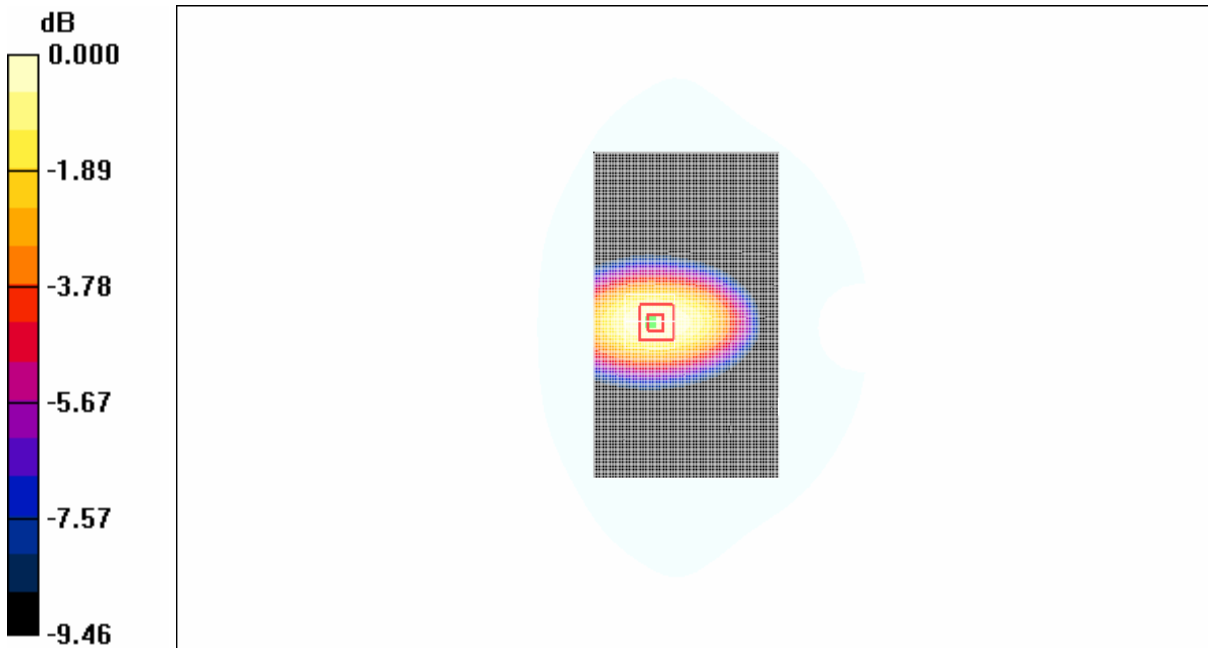
Test Position 13 Low/Zoom Scan (7x7x7)/Cube 0: Measurement grid: dx=5mm, dy=5mm, dz=5mm

Reference Value = 29.0 V/m; Power Drift = 0.200 dB

Peak SAR (extrapolated) = 1.29 W/kg

SAR(1 g) = 0.979 mW/g; SAR(10 g) = 0.687 mW/g

Maximum value of SAR (measured) = 1.04 mW/g



0 dB = 1.04mW/g

Fig. 28 Test Position 13 CDMA 835MHz CH1013

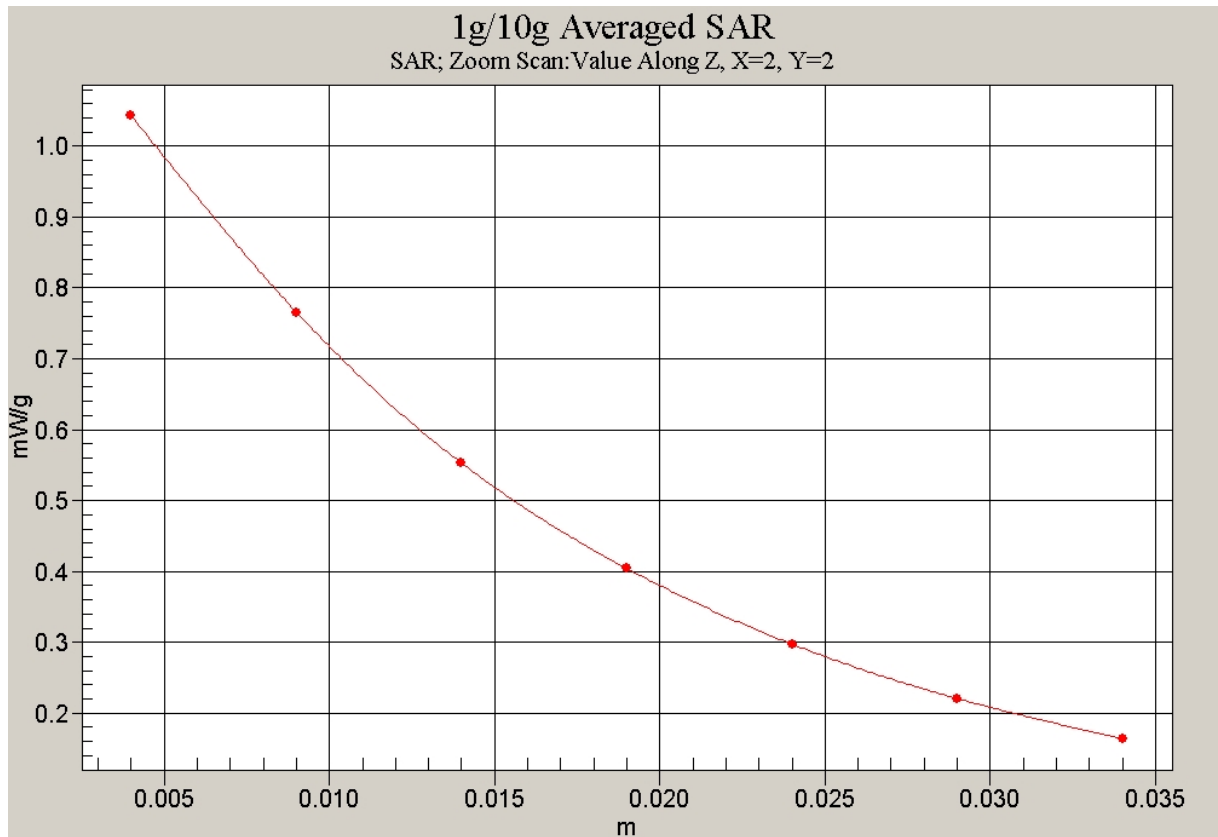


Fig. 30 Z-Scan at power reference point (CDMA 835MHz CH1013)

ANNEX D: SYSTEM VALIDATION RESULTS

835MHzDAE536Probe1736

Electronics: DAE3 Sn536

Communication System: CW Frequency: 835 MHz Duty Cycle: 1:1

Probe: ET3DV6 - SN1736 ConvF(6.51, 6.51, 6.51)

835MHz/Area Scan (101x101x1): Measurement grid: dx=10mm, dy=10mm

Reference Value = 56.8 V/m; Power Drift = -0.0 dB

Maximum value of SAR (interpolated) = 2.68 mW/g

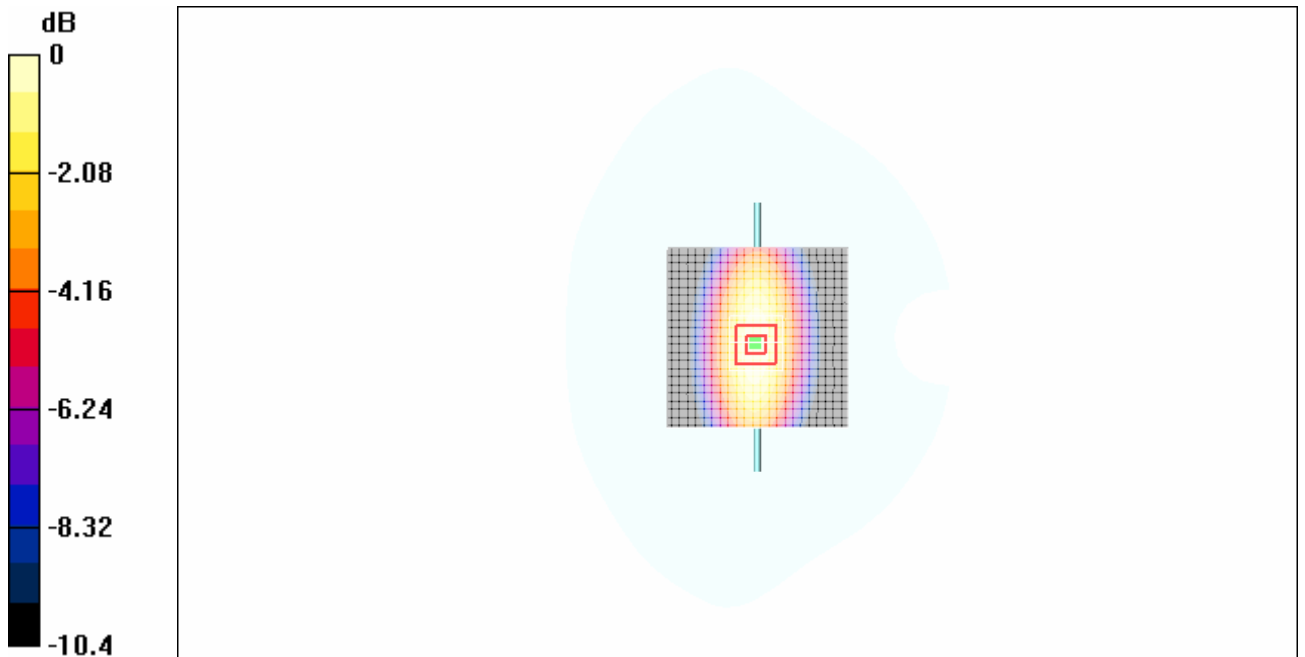
835MHz/Zoom Scan (7x7x7)/Cube 0: Measurement grid: dx=5mm, dy=5mm, dz=5mm

Reference Value = 56.8 V/m; Power Drift = -0.0 dB

Maximum value of SAR (measured) = 2.69 mW/g

Peak SAR (extrapolated) = 3.67 W/kg

SAR(1 g) = 2.48 mW/g; SAR(10 g) = 1.62 mW/g



0 dB = 2.69mW/g

Fig.31 validation 835MHz 250mW

Telecommunication Metrology Center of Ministry of Information Industry

No.SAR2006001

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ANNEX E: PROBE CALIBRATION CERTIFICATE

**Calibration Laboratory of
Schmid & Partner
Engineering AG**
Zeughausstrasse 43, 8004 Zurich, Switzerland



S Schweizerischer Kalibrierdienst
C Service suisse d'étalonnage
S Servizio svizzero di taratura
S Swiss Calibration Service

Accredited by the Swiss Federal Office of Metrology and Accreditation
The Swiss Accreditation Service is one of the signatories to the EA
Multilateral Agreement for the recognition of calibration certificates

Accreditation No.: **SCS 108**

Client **TMC-Auden**

Certificate No: **ET3-1736_Nov05**

CALIBRATION CERTIFICATE

Object	ET3DV6 - SN:1736
Calibration procedure(s)	QA CAL-01.v5 Calibration procedure for dosimetric E-field probes
Calibration date:	November 25, 2005
Condition of the calibrated item	In Tolerance

This calibration certificate documents the traceability to national standards, which realize the physical units of measurements (SI).
The measurements and the uncertainties with confidence probability are given on the following pages and are part of the certificate.

All calibrations have been conducted in the closed laboratory facility: environment temperature (22 ± 3)°C and humidity < 70%.

Calibration Equipment used (M&TE critical for calibration)

Primary Standards	ID #	Cal Date (Calibrated by, Certificate No.)	Scheduled Calibration
Power meter E4419B	GB41293874	3-May-05 (METAS, No. 251-00466)	May-06
Power sensor E4412A	MY41495277	3-May-05 (METAS, No. 251-00466)	May-06
Power sensor E4412A	MY41498087	3-May-05 (METAS, No. 251-00466)	May-06
Reference 20 dB Attenuator	SN: S5086 (20b)	3-May-05 (METAS, No. 251-00467)	May-06
Reference Probe ES3DV2	SN: S5086 (20b)	3-May-05 (METAS, No. 251-00467)	May-06
DAE4	SN: 3013	7-Jan-05 (SPEAG, No. ES3-3013_Jan05)	Jan-06
Reference Probe ES3DV2	SN: 907	21-Jun-05 (SPEAG, No. DAE4-907_Jun05)	Jun-06

Secondary Standards	ID #	Check Date (in house)	Scheduled Check
RF generator HP 8648C	US3642U01700	4-Aug-99 (SPEAG, in house check Dec-03)	In house check: Dec-05
Network Analyzer HP 8753E	US37390585	18-Oct-01 (SPEAG, in house check Nov-04)	In house check: Nov 05

	Name	Function	Signature
Calibrated by:	Nico Vetterli	Laboratory Technician	

	Name	Function	Signature
Approved by:	Katja Pokovic	Technical Manager	

Issued: November 25, 2005

This calibration certificate shall not be reproduced except in full without written approval of the laboratory.

Calibration Laboratory of
Schmid & Partner
Engineering AG
Zeughausstrasse 43, 8004 Zurich, Switzerland



S Schweizerischer Kalibrierdienst
C Service suisse d'étalonnage
S Servizio svizzero di taratura
S Swiss Calibration Service

Accredited by the Swiss Federal Office of Metrology and Accreditation
The Swiss Accreditation Service is one of the signatories to the EA
Multilateral Agreement for the recognition of calibration certificates

Accreditation No.: SCS 108

Glossary:

TSL	tissue simulating liquid
NORM _{x,y,z}	sensitivity in free space
ConvF	sensitivity in TSL / NORM _{x,y,z}
DCP	diode compression point
Polarization φ	φ rotation around probe axis
Polarization ϑ	ϑ rotation around an axis that is in the plane normal to probe axis (at measurement center), i.e., $\vartheta = 0$ is normal to probe axis

Calibration is Performed According to the Following Standards:

- IEEE Std 1528-2003, "IEEE Recommended Practice for Determining the Peak Spatial-Averaged Specific Absorption Rate (SAR) in the Human Head from Wireless Communications Devices: Measurement Techniques", December 2003
- CENELEC EN 50361, "Basic standard for the measurement of Specific Absorption Rate related to human exposure to electromagnetic fields from mobile phones (300 MHz - 3 GHz), July 2001

Methods Applied and Interpretation of Parameters:

- NORM_{x,y,z}*: Assessed for E-field polarization $\vartheta = 0$ ($f \leq 900$ MHz in TEM-cell; $f > 1800$ MHz: R22 waveguide). *NORM_{x,y,z}* are only intermediate values, i.e., the uncertainties of *NORM_{x,y,z}* does not effect the E^2 -field uncertainty inside TSL (see below *ConvF*).
- NORM(f)_{x,y,z}* = *NORM_{x,y,z}* * *frequency_response* (see Frequency Response Chart). This linearization is implemented in DASY4 software versions later than 4.2. The uncertainty of the frequency response is included in the stated uncertainty of *ConvF*.
- DCP_{x,y,z}*: DCP are numerical linearization parameters assessed based on the data of power sweep (no uncertainty required). DCP does not depend on frequency nor media.
- ConvF and Boundary Effect Parameters*: Assessed in flat phantom using E-field (or Temperature Transfer Standard for $f \leq 800$ MHz) and inside waveguide using analytical field distributions based on power measurements for $f > 800$ MHz. The same setups are used for assessment of the parameters applied for boundary compensation (alpha, depth) of which typical uncertainty values are given. These parameters are used in DASY4 software to improve probe accuracy close to the boundary. The sensitivity in TSL corresponds to *NORM_{x,y,z}* * *ConvF* whereby the uncertainty corresponds to that given for *ConvF*. A frequency dependent *ConvF* is used in DASY version 4.4 and higher which allows extending the validity from ± 50 MHz to ± 100 MHz.
- Spherical isotropy (3D deviation from isotropy)*: in a field of low gradients realized using a flat phantom exposed by a patch antenna.
- Sensor Offset*: The sensor offset corresponds to the offset of virtual measurement center from the probe tip (on probe axis). No tolerance required.

ET3DV6 SN:1736

November 25, 2005

Probe ET3DV6

SN:1736

Manufactured:	September 27, 2002
Last calibrated:	July 14, 2005
Recalibrated:	November 25, 2005

Calibrated for DASY Systems

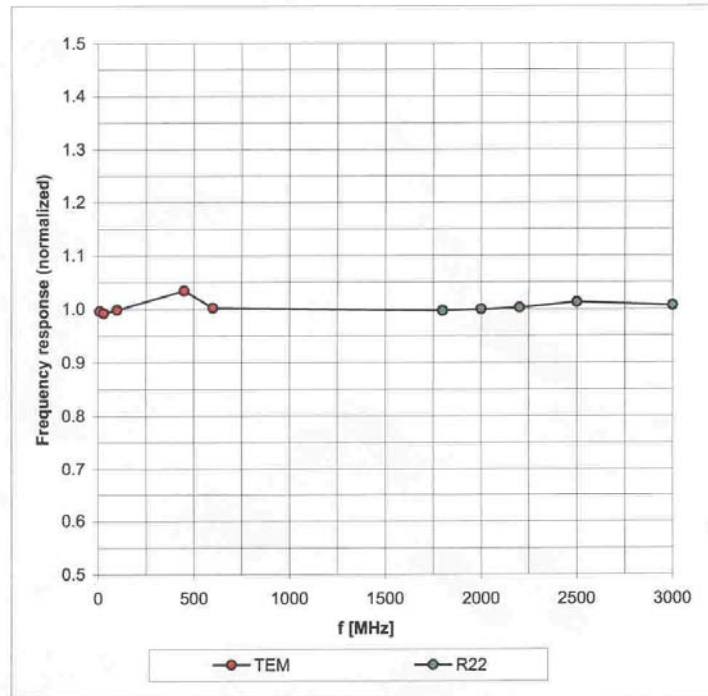
(Note: non-compatible with DASY2 system!)

ET3DV6 SN:1736

November 25, 2005

Frequency Response of E-Field

(TEM-Cell:ifi110 EXX, Waveguide: R22)

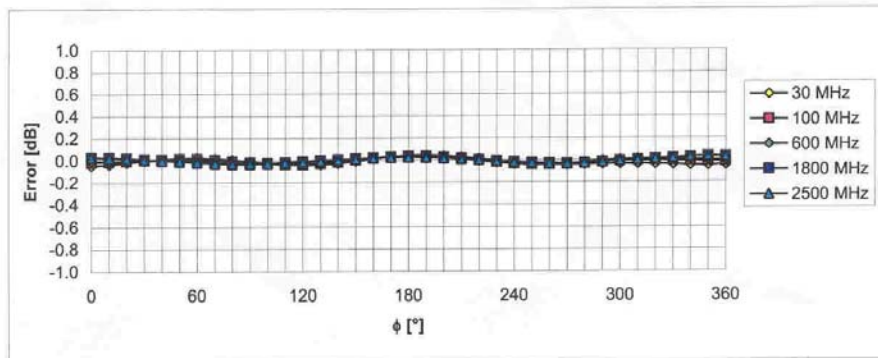
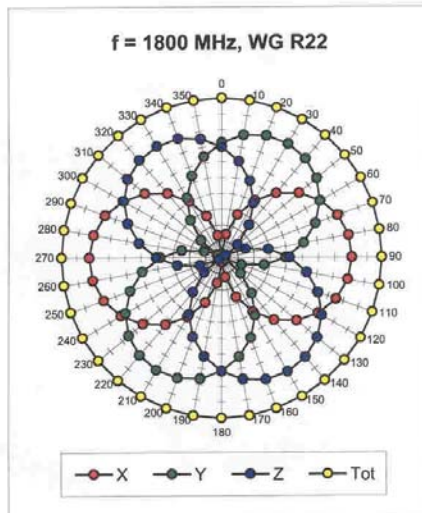
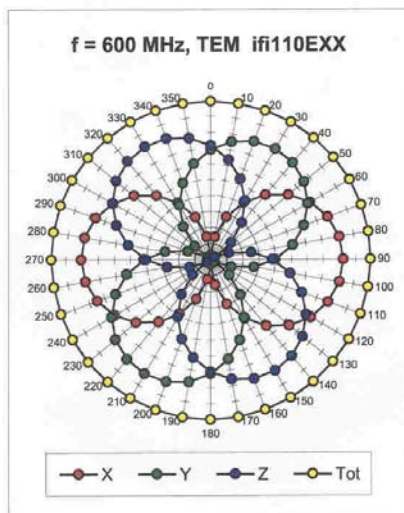


Uncertainty of Frequency Response of E-field: $\pm 6.3\%$ ($k=2$)

ET3DV6 SN:1736

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Receiving Pattern (ϕ), $\vartheta = 0^\circ$

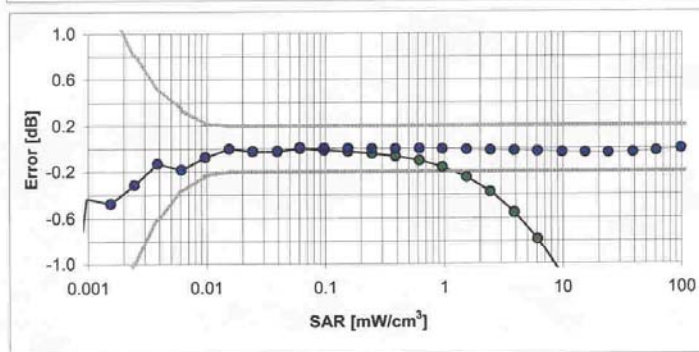
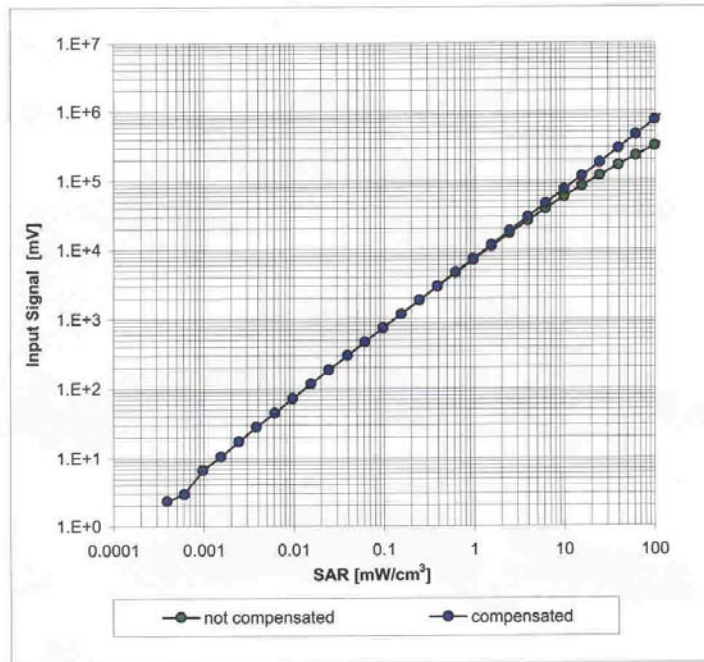


Uncertainty of Axial Isotropy Assessment: $\pm 0.5\%$ ($k=2$)

ET3DV6 SN:1736

November 25, 2005

Dynamic Range $f(SAR_{head})$
(Waveguide R22, $f = 1800$ MHz)

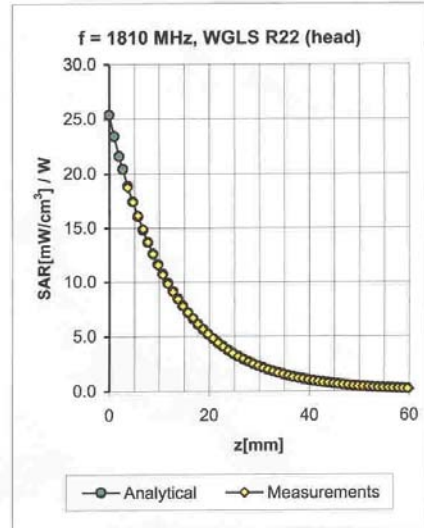
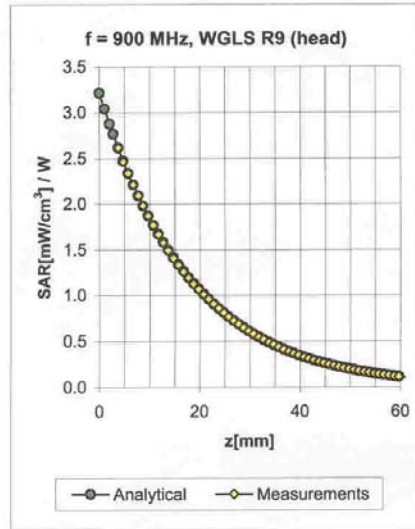


Uncertainty of Linearity Assessment: $\pm 0.6\%$ ($k=2$)

ET3DV6 SN:1736

November 25, 2005

Conversion Factor Assessment



f [MHz]	Validity [MHz] ^c	TSL	Permittivity	Conductivity	Alpha	Depth	ConvF Uncertainty
900	± 50 / ± 100	Head	41.5 ± 5%	0.97 ± 5%	0.56	1.85	6.51 ± 11.0% (k=2)
1810	± 50 / ± 100	Head	40.0 ± 5%	1.40 ± 5%	0.57	2.47	5.40 ± 11.0% (k=2)
2450	± 50 / ± 100	Head	39.2 ± 5%	1.80 ± 5%	0.62	2.29	4.67 ± 11.8% (k=2)
450	± 50 / ± 100	Body	56.7 ± 5%	0.94 ± 5%	0.12	1.61	7.74 ± 13.3% (k=2)
900	± 50 / ± 100	Body	55.0 ± 5%	1.05 ± 5%	0.47	2.15	6.45 ± 11.0% (k=2)
1810	± 50 / ± 100	Body	53.3 ± 5%	1.52 ± 5%	0.53	2.78	4.88 ± 11.0% (k=2)
2450	± 50 / ± 100	Body	52.7 ± 5%	1.95 ± 5%	0.65	2.11	4.35 ± 11.8% (k=2)

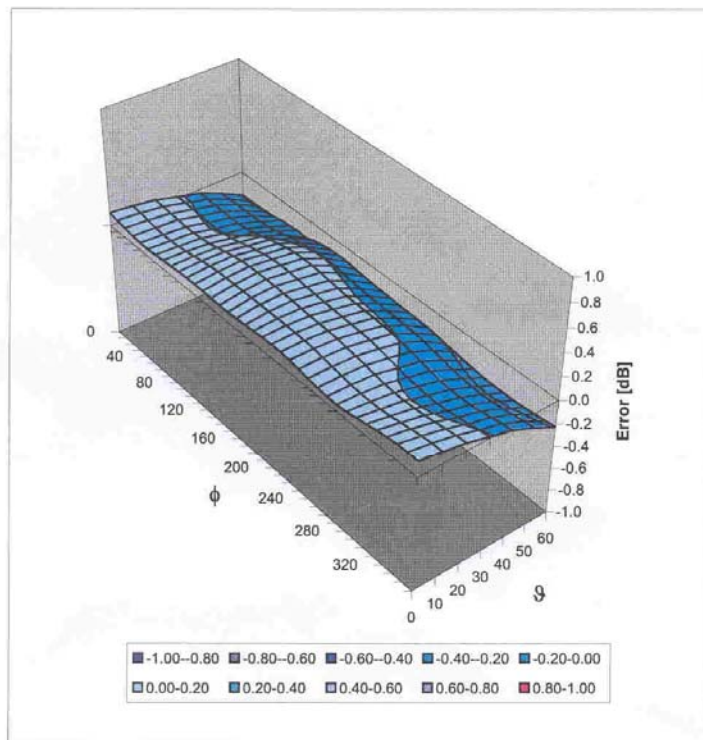
^c The validity of ± 100 MHz only applies for DASY v4.4 and higher (see Page 2). The uncertainty is the RSS of the ConvF uncertainty at calibration frequency and the uncertainty for the Indicated frequency band.

ET3DV6 SN:1736

November 25, 2005

Deviation from Isotropy in HSL

Error (ϕ , ϑ), $f = 900$ MHz



Uncertainty of Spherical Isotropy Assessment: $\pm 2.6\%$ ($k=2$)